Docket Number: 081468-0306882 Client Reference: P-1741.000-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

the Application of

STREEFKERK et al.

Group Art Unit: 2851

Application No.: 10/719,683

Examiner:

Filed: November 24, 2003

Confirmation No.: 1907

For:

LITHOGRAPHIC APPARATUS AND DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

JUN 1 4 2004 24

Pursuant to 37 C.F.R. 1.56, the attention of the Patent and Trademark Office is hereby directed to the following U.S. patent application(s):

Examiner's Initials	First Inventor	Application No.	Filing Date	Enclosed
	DIERICHS (081468-0308270)	10/775,326	02/11/2004	☒ Specification☒ Drawings☒ Other: stamped receipt card
	DUINEVELD et al. (081468-0308101)	10/773,461	02/09/2004	☑ Specification☑ Drawings☑ Other: stamped receipt card
	FLAGELLO et al. (081468-0302644)	10/698,012	10/31/2003	☑ Specification☑ Drawings☑ Other: stamped receipt card
	SUWA et al. (Reissue Application of U.S. Patent No. 6,191,429 B1)	10/367,910	02/19/2003	☑ Specification☑ Drawings☐ Other: stamped receipt card

^{*}The Examiner's initials adjacent a citation indicates he/she has considered the cited application relative to the subject application.

It is respectfully requested that these applications and the art cited therein during examination be expressly considered during the prosecution of this application and be made of record in this application. The identification of the above U.S. patent applications is not to be construed as a waiver of secrecy as to those applications now or upon issuance of the present application as a patent.

PLEASE DO NOT PRINT the above information on the patent which results from this application.

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Consideration of each listed application is earnestly solicited since unpublished patent applications are contemplated as IDS material; see the exception in Rule 98(a)(2)(iii) and note the penultimate sentence of MPEP 609.

Further, in keeping with MPEP 609, subsec. C(2), 2nd para., line 10 to end of the paragraph (especially note lines 18-25) **PLEASE RETURN A COPY OF THIS LETTER** with the Examiner's initials adjacent each above listing so that applicant will know that each listed application has been considered as required by PTO policy.

Secondly, please consider each document which is listed on the attached Form PTO-1449 and return a copy of that form with the Examiner's initials adjacent each citation, a copy of each document enclosed except for any U.S. patents and published patent applications. It is respectfully requested that these documents listed on the Form PTO-1449 be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

Respectfully Submitted,

PILLSBURY WINTH

V Ha

Jean-Paul G. Hoffmah

Registration Number 42663 Customer Number: 00909

Date: June 14, 2004

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Name	FORM PTO-1449 (modified) To: U.S. Department of Commerce (PW FORM PAT-1449) Patent and Trademark Office						Atty. Dkt. No.	M#			Client Ref.					
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